



TECHNICAL REPORT

LTE;
Evolved Universal Terrestrial Radio Access (E-UTRA)
and Evolved Universal Terrestrial
Radio Access Network (E-UTRAN);
Derivation of test tolerances
for Radio Resource Management (RRM) conformance tests
(3GPP TR 36.903 version 15.2.0 Release 15)



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Introduction

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1 Scope

The present document specifies a general method used to derive Test Tolerances for Radio Resource Management tests, and establishes a system for relating the Test Tolerances to the measurement uncertainties of the Test System.

The test cases which have been analysed to determine Test Tolerances are included as .zip files.

The present document is applicable from Release 8 up to the release indicated on the front page of the present Terminal conformance specifications.

2 References

The following documents contain provisions which, through reference in this text, constitute provisions of the present document.

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- [1] 3GPP TR 21.905: "Vocabulary for 3GPP Specifications".
- [2] ETSI ETR 273-1-2: "Improvement of radiated methods of measurement (using test sites) and evaluation of the corresponding measurement uncertainties; Part 1: Uncertainties in the measurement of mobile radio equipment characteristics; Sub-part 2: Examples and annexes".
- [3] 3GPP TS 34.121-1: "Terminal conformance specification, Radio transmission and reception (FDD), Release 8".
- [4] 3GPP TS 36.521-1: "User Equipment (UE) conformance specification, Radio transmission and reception Part 1: conformance testing, Release 8".
- [5] 3GPP TS 36.521-3: "User Equipment (UE) conformance specification, Radio transmission and reception Part 3: Radio Resource Management (RRM) conformance testing, Release 8".
- [6] 3GPP TS 36.141: "E-UTRA Base Station (BS) conformance testing, Release 8"
- [7] 3GPP TS 36.211: "E-UTRA Physical Channels and Modulation, Release 8"
- [8] 3GPP TS 37.571-1: "Universal Terrestrial Radio Access (UTRA) and Evolved UTRA (E-UTRA) and Evolved Packet Core (EPC); User Equipment (UE) conformance specification for UE positioning; Part 1: Terminal conformance".

3 Definitions, symbols and abbreviations

3.1 Definitions

For the purposes of the present document, the terms and definitions given in TR 21.905 [1] apply. A term defined in the present document takes precedence over the definition of the same term, if any, in TR 21.905 [1].

Other definitions used in the present document are listed in 3GPP TS 36.521-3 [5] or 3GPP TS 36.141 [6].

3.2 Symbols

Symbols used in the present document are listed in 3GPP TR 21.905 [1], 3GPP TS 36.521-3 [5] or 3GPP TS 36.141 [6].

3.3 Abbreviations

For the purposes of the present document, the abbreviations given in TR 21.905 [1] apply. An abbreviation defined in the present document takes precedence over the definition of the same abbreviation, if any, in TR 21.905 [1].

Other abbreviations used in the present document are listed in 3GPP TS 36.521-3 [5] or 3GPP TS 36.141 [6].

4 General Principles

4.1 Principle of Superposition

For multi-cell tests there are several cells each generating various Physical channels. In general cells are combined along with AWGN, so the signal and noise seen by the UE may be determined by more than one cell.

Since several cells may contribute towards the overall power applied to the UE, a number of test system uncertainties affect the signal and noise seen by the UE. The aim of the superposition method is to vary each controllable parameter of the test system separately, and to establish its effect on the critical parameters as seen by the UE receiver. The superposition principle then allows the effect of each test system uncertainty to be added, to calculate the overall effect.

The contributing test system uncertainties shall form a minimum set for the superposition principle to be applicable.

4.2 Sensitivity analysis

A change in any one channel level or channel ratio generated at source does not necessarily have a 1:1 effect at the UE. The effect of each controllable parameter of the test system on the critical parameters as seen by the UE receiver shall therefore be established. As a consequence of the sensitivity scaling factors not necessarily being unity, the test system uncertainties cannot be directly applied as test tolerances to the critical parameters as seen by the UE.

EXAMPLE: In many of the tests described, the \hat{E}_s / I_{ot} is one of the critical parameters at the UE. Scaling factors are used to model the sensitivity of the \hat{E}_s / I_{ot} to each test system uncertainty. When the scaling factors have been determined, the superposition principle then allows the effect of each test system uncertainty to be added, to give the overall variability in the critical parameters as seen at the UE.

There are often constraints on several parameters at the UE. The aim of the sensitivity analysis, together with the acceptable test system uncertainties, is to ensure that the variability in each of these parameters is controlled within the limits necessary for the specification to apply. The test has then been conducted under valid conditions.

4.3 Statistical combination of uncertainties

The acceptable uncertainties of the test system are specified as the measurement uncertainty tolerance interval for a specific measurement that contains 95 % of the performance of a population of test equipment, in accordance with 3GPP TS 36.521-3 [5] clause F.1. In the RRM tests covered by the present document, the Test System shall enable the stimulus signals in the test case to be adjusted to within the specified range, with an uncertainty not exceeding the specified values.

The method given in the present document combines the acceptable uncertainties of the test system, to give the overall variability in the critical parameters as seen at the UE. Since the process does not add any new uncertainties, the method of combination should be chosen to maintain the same tolerance interval for the combined uncertainty as is already specified for the contributing test system uncertainties.

The basic principle for combining uncertainties is in accordance with ETR 273-1-2 [2]. In summary, the process requires 3 steps:

- a) Express the value of each contributing uncertainty as a one standard deviation figure, from knowledge of its numeric value and its distribution.
- b) Combine all the one standard deviation figures as root-sum-squares, to give the one standard deviation value for the combined uncertainty.
- c) Expand the combined uncertainty by a coverage factor, according to the tolerance interval required.

Provided that the contributing uncertainties have already been obtained using this method, using a coverage factor of 2, further stages of combination can be achieved by performing step b) alone, since steps a) and c) simply divide by 2 and multiply by 2 respectively.

The root-sum-squares method is therefore used to maintain the same tolerance interval for the combined uncertainty as is already specified for the contributing test system uncertainties. In some cases where correlation between contributing uncertainties has an adverse effect, the method is modified in accordance with clause 4.4.5 of the present document.

In each analysis, the uncertainties are assumed to be uncorrelated, and are added result root-sum-square unless otherwise stated.

The combination of uncertainties is performed using dB values for simplicity. It has been shown that using dB uncertainty values gives a slightly worse combined uncertainty result than using linear values for the uncertainties. The analysis method therefore errs on the safe side.

4.4 Correlation between uncertainties

The statistical (root-sum-square) addition of uncertainties is based on the assumption that the uncertainties are independent of each other. For realisable test systems, the uncertainties may not be fully independent. The validity of the method used to add uncertainties depends on both the type of correlation and on the way in which the uncertainties affect the test requirements.

Clauses 4.4.1 to 4.4.3 give examples to illustrate different types of correlation.

Clauses 4.4.4 to 4.4.7 show how the scenarios applicable to multi-cell RRM tests are treated.

4.4.1 Uncorrelated uncertainties

The graph shows an example of two test system uncertainties, A and B, which affect a test requirement. Each sample from a population of test systems has a specific value of error in parameter A, and a specific value of error in parameter B. Each dot on the graph represents a sample from a population of test systems, and is plotted according to its error values for parameters A and B.

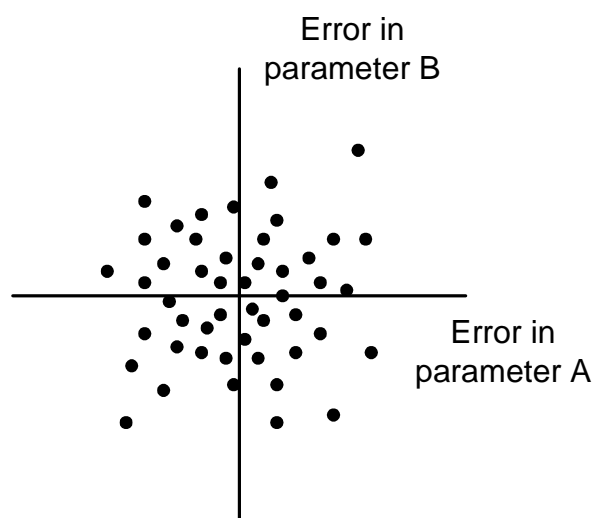


Figure 4.4.1.1: Example of two test system uncertainties affecting a test requirement

It can be seen that a positive value of error in parameter A, for example, is equally likely to occur with either a positive or a negative value of error in parameter B. This is expected when two parameters are uncorrelated, such as two uncertainties which arise from different and unrelated parts of the test system.

4.4.2 Positively correlated uncertainties

The graph shows an example of two test system uncertainties, A and B, which affect a test requirement. Each sample from a population of test systems has a specific value of error in parameter A, and a specific value of error in parameter B. Each dot on the graph represents a sample from a population of test systems, and is plotted according to its error values for parameters A and B.

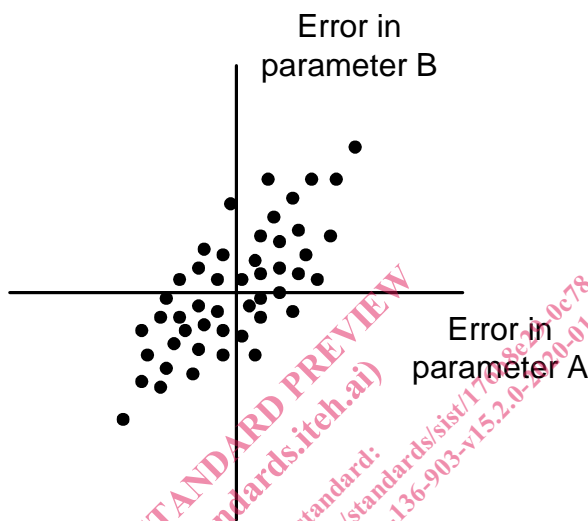


Figure 4.4.2.1: Example of two test system uncertainties affecting a test requirement

It can be seen that a positive value of error in parameter A, for example, is more likely to occur with a positive value of error in parameter B and less likely to occur with a negative value of error in parameter B. This can occur when the two uncertainties arise from similar parts of the test system, or when one component of the uncertainty affects both parameters in a similar way.

In an extreme case, if the error in parameter A and the error in parameter B came from the same sources of uncertainty, and no others, the dots would lie on a straight line of slope +1.

4.4.3 Negatively correlated uncertainties

The graph shows an example of two test system uncertainties, A and B, which affect a test condition. Each sample from a population of test systems has a specific value of error in parameter A, and a specific value of error in parameter B. Each dot on the graph represents a sample from a population of test systems, and is plotted according to its error values for parameters A and B.

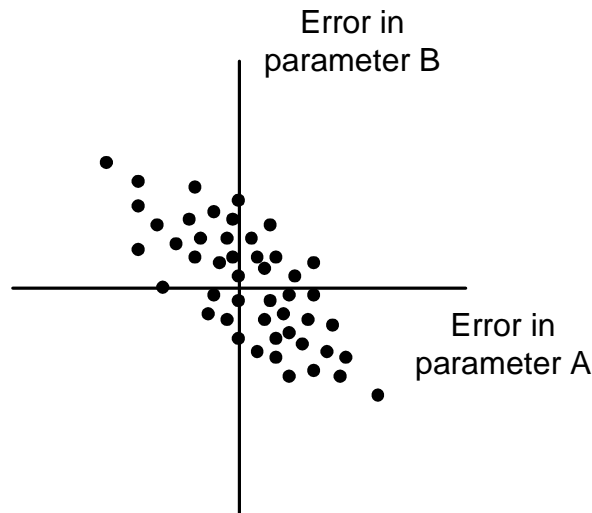


Figure 4.4.3.1: Example of two test system uncertainties affecting a test condition

It can be seen that a positive value of error in parameter A, for example, is more likely to occur with a negative value of error in parameter B and less likely to occur with a positive value of error in parameter B. This effect can theoretically occur, and is included for completeness, but is unlikely in a practical test system.

4.4.4 Treatment of uncorrelated uncertainties

If two uncertainties are uncorrelated, they are added statistically in the analysis. Provided that each uncertainty is already expressed as an expanded uncertainty with coverage factor 2, the contributing uncertainties are added root-sum-squares to give a combined uncertainty which also has coverage factor 2, and the 95% tolerance interval is maintained.

This is the default assumption.

4.4.5 Treatment of positively correlated uncertainties with adverse effect

If two test system uncertainties are positively correlated, and if they affect the value of a critical parameter in the same direction, the combined effect may be greater than predicted by adding the contributing uncertainties root-sum-squares.

In this scenario the two uncertainties are added worst-case in the analysis. Provided that each uncertainty is already expressed as an expanded uncertainty with coverage factor 2, the combined uncertainty will cover a 95% tolerance interval even when the two contributing uncertainties are fully correlated. If the two contributing uncertainties are less than fully correlated, the combined uncertainty will cover a tolerance interval greater than 95%.

4.4.6 Treatment of positively correlated uncertainties with beneficial effect

If two test system uncertainties are positively correlated, and if they affect the value of a critical parameter in opposite directions, the combined effect will be less than predicted by adding the contributing uncertainties root-sum-squares.

In this scenario the two uncertainties are added statistically in the analysis. Provided that each uncertainty is already expressed as an expanded uncertainty with coverage factor 2, the combined uncertainty will cover a 95% tolerance interval when the two contributing uncertainties are uncorrelated. If the two contributing uncertainties are positively correlated, the combined uncertainty will cover a tolerance interval greater than 95%.

4.4.7 Treatment of negatively correlated uncertainties

Negatively correlated uncertainties are excluded by the assumptions. This has been agreed as an acceptable restriction on practical test systems, as the mechanisms which produce correlation generally arise from similarities between two parts of the test system, and therefore produce positive correlation.

5 Grouping of test cases defined in TS 36.521-3

The Test cases are grouped from the viewpoint of efficiently defining the uncertainties and test tolerances. Tests in the same group generally have the same type of uncertainties, given in more detail in Annex B.

A group of test cases having significant differences from those already listed, in respect of uncertainties and test tolerance analysis, will require a new row in the Table.

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